

In situ analysis of the nucleation of O- and Zn-polar ZnO nanowires
using synchrotron-based X-ray diffraction

Valentina Cantelli,¹ Sophie Guillemin,¹ Eirini Sarigiannidou,¹ Francesco Carlá,² Bruno Bérini,³ Jean-Michel Chauveau,^{3,4} Dillon D. Fong,⁵ Hubert Renevier,^{1*} and Vincent Consonni.^{1*}

¹ *Université Grenoble Alpes, CNRS, Grenoble INP, LMGP, F-38000 Grenoble, France.*

² *ESRF, 71 avenue des Martyrs, F-38000 Grenoble France.*

³ *Université Versailles Saint-Quentin, Université Paris Saclay, CNRS, GEMAC, F-78035 Versailles, France.*

⁴ *Université Côte d'Azur, CNRS, CRHEA, Rue Bernard Gregory, F-06560 Valbonne, France.*

⁵ *Materials Science Division, Argonne National Laboratory, 9700 S. Cass Ave., Lemont, IL-60439, United States.*

*Corresponding authors: hubert.renevier@grenoble-inp.fr and vincent.consonni@grenoble-inp.fr

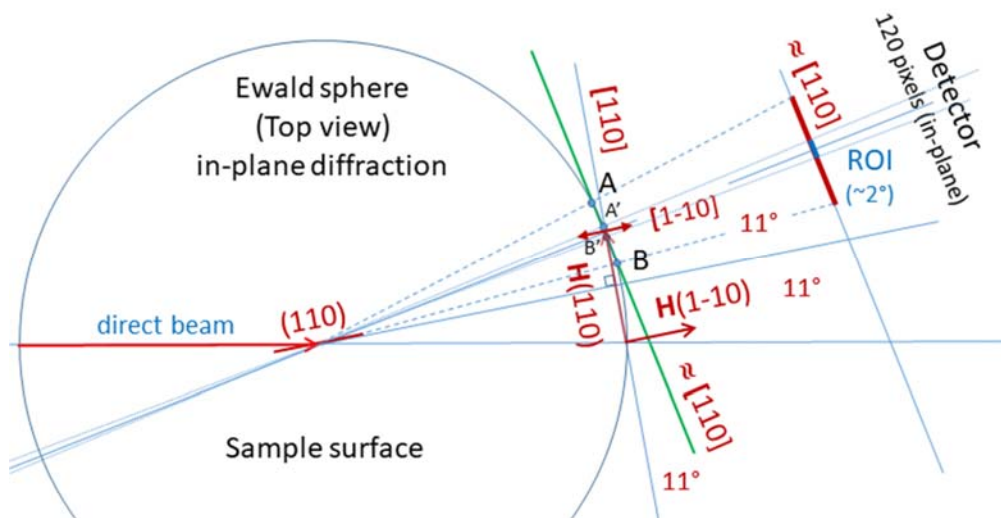


Fig. S1 Schematic representing the configuration used during the in-plane XRD measurements.

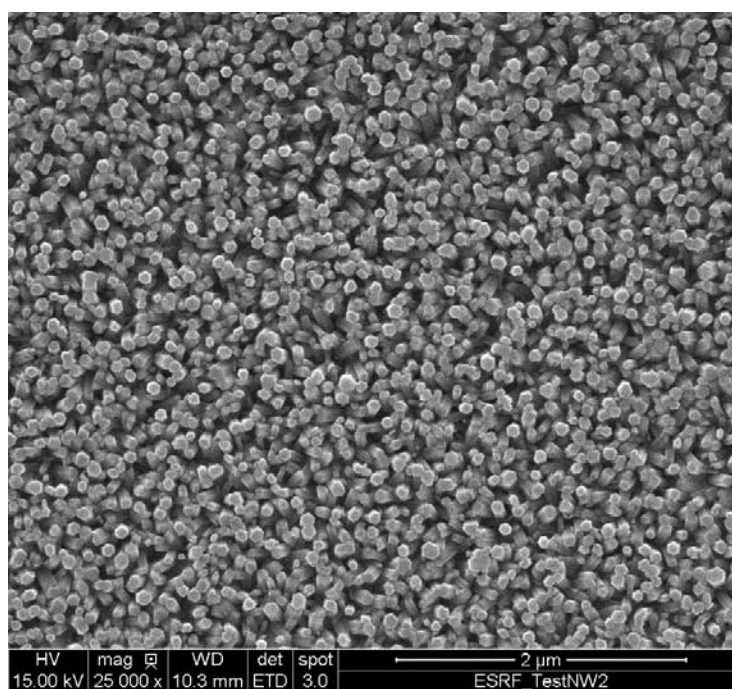


Fig. S2 Typical FESEM image of ZnO NWs grown on a *c*-axis oriented polycrystalline ZnO seed layer using the designed leak-tight growth cell.